TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7SZ02AFE

2 Input NOR Gate

Features

• High output drive: ±24 mA (typ.)

$$@VCC = 3 V$$

• Super high speed operation: tpD 2.4 ns (typ.)

$$@V_{CC} = 5 \text{ V}, 50 \text{ pF}$$

• Operation voltage range: $V_{CC \text{ (opr)}} = 1.8 \sim 5.5 \text{ V}$

• Supply voltage data retention: $V_{CC} = 1.5 \sim 5.5 \text{ V}$

• Latch-up performance: ±500 mA

• ESD performance: Human body model > $\pm 2000 \text{ V}$

Machine model >
$$\pm 200 \text{ V}$$

Power down protection is provided on all inputs.

 $\bullet~$ Matches the performance of TC74LCX series when operated at 3.3 V VCC

• Input rise and fall time (tr, tf) (recommended operation condition)

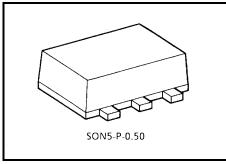
@Vcc = 1.8 V, 2.5 V
$$\pm$$
 0.2 V: 0~20 ns/V

@V_{CC} = $3.3 \text{ V} \pm 0.3 \text{ V}$: $0 \sim 10 \text{ ns/V}$

 $@V_{CC} = 5.5 \text{ V} \pm 0.5 \text{ V}: 0 \sim 5 \text{ ns/V}$



Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~6	V
DC input voltage	V _{IN}	-0.5~6	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	V
Input diode current	I _{IK}	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±50	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	P _D	150	mW
Storage temperature	T _{stg}	-65~150	°C
Lead temperature (10 s)	TL	260	°C



Weight: 0.003 g (typ.)

Electrical Characteristics

DC Characteristics

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Test		Test	Test Condition			Ta = 25°C		Ta = -40~85°C			
Characteristics	Symbol Circuit				V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit
High-level input			1.8	0.75 × V _{CC}	_	_	0.75 × V _{CC}		V		
voltage	V _{IH} —		_		2.3- 5.5	0.7 × V _{CC}	_	_	0.7 × V _{CC}	_	
Low-level input						_	_	0.25 × V _{CC}	_	0.25 × V _{CC}	V
voltage				_	2.3- 5.5	_	ı	0.3 × V _{CC}	ı	0.3 × V _{CC}	v
					1.8	1.7	1.8		1.7		V
				Jour = 100 u/A	2.3	2.2	2.3		2.2		
	High-level voltage		V _{IN} = V _{IL}	$I_{OH} = -100 \mu A$	3.0	2.9	3.0	_	2.9	_	
					4.5	4.4	4.5	_	4.4		
output voltage				$I_{OH} = -8 \text{ mA}$	2.3	1.9	2.15	_	1.9		
			$I_{OH} = -16 \text{ mA}$	3.0	2.4	2.8		2.4	_		
			$I_{OH} = -24 \text{ mA}$	3.0	2.3	2.68		2.3			
				$I_{OH} = -32 \text{ mA}$	4.5	3.8	4.2		3.8		
				$I_{OL} = 100 \ \mu A$	1.8	_	0	0.1		0.1	
					2.3	_	0	0.1		0.1	
					3.0	_	0	0.1	_	0.1	
Low-level output voltage VoL —		V _{IN} =		4.5	_	0	0.1	_	0.1	V	
	_	V _{IH} or	I _{OL} = 8 mA	2.3	_	0.1	0.3	_	0.3		
			I _{OL} = 16 mA	3.0	_	0.15	0.4	_	0.4		
			I _{OL} = 24 mA	3.0	_	0.22	0.55	_	0.55		
				I _{OL} = 32 mA	4.5	_	0.22	0.55		0.55	
Input leakage current	I _{IN}	_	V _{IN} = 5.5 V or GND		0- 5.5		_	±1	_	±10	μА
Quiescent supply current	Icc	_	V _{IN} = V _{CC} or GND		5.5	_		2		20	μА

AC Characteristics (input: $t_r = t_f = 3 \text{ ns}$)

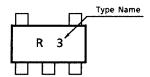
Characteristics Symbol Ter		Test	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit
Characteristics Symbol	Circuit	V _{CC} (V)		Min	Тур.	Max	Min	Max	Offic	
Propagation delay ^t PLH time t _{PHL}				1.8	2.0	4.4	9.5	2.0	10.0	
	_	$C_L = 15 \text{ pF},$ $R_L = 1 \text{ M}\Omega$	2.5 ± 0.2	0.8	2.9	6.5	0.8	7.0	ns	
			3.3 ± 0.3	0.5	2.3	4.5	0.5	4.7		
			5.0 ± 0.5	0.5	1.9	3.9	0.5	4.1		
		$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$	3.3 ± 0.3	1.5	2.9	5.0	1.5	5.2		
			5.0 ± 0.5	0.8	2.4	4.3	0.8	4.5		
Input capacitance	C _{IN}	_	_	0-5.5	_	4	_	_	_	pF
Power dissipation capacitance CPD	C	C _{PD} —	(Note)	3.3	_	19	_	_	_	- pF
	OPD			5.5	_	27		_	_	

Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

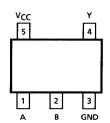
Average operating current can be obtained by the equation.

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Marking



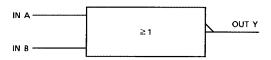
Pin Assignment (top view)



Truth Table

Α	В	Υ
L	L	Н
L	Н	L
Н	L	L
Н	Н	L

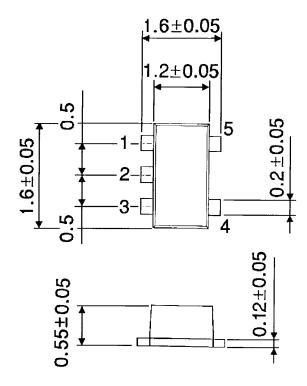
Logic Diagram



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Package Dimensions

SON5-P-0.50 Unit: mm



Weight: 0.003 g (typ.)

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